

<b>Notice of References Cited</b>	Application/Control No. 10/737,064	Applicant(s)/Patent Under Reexamination HORNBACK ET AL.	
	Examiner Sath V. Perungavoor	Art Unit 2624	Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,339,172 A	08-1994	Robinson, David C.	358/462
*	B	US-5,434,983 A	07-1995	Yaso et al.	710/110
*	C	US-5,461,682 A	10-1995	Nomura, Keiichi	382/232
*	D	US-5,787,414 A	07-1998	Miike et al.	707/2
*	E	US-5,928,335 A	07-1999	Morita, Tetsuya	709/203
*	F	US-5,933,686 A	08-1999	Ootsuka et al.	399/87
*	G	US-6,055,017 A	04-2000	Shen et al.	375/240.11
*	H	US-6,084,686 A	07-2000	Ushida, Katsutoshi	358/1.16
*	I	US-6,233,017 B1	05-2001	Chaddha, Navin	375/240.12
*	J	US-2001/0041017 A1	11-2001	DE QUEIROZ, RICARDO	382/253
*	K	US-6,408,024 B1	06-2002	Nagao et al.	375/240.01
*	L	US-2003/0007703 A1	01-2003	Roylance, Eugene A.	382/303
*	M	US-6,563,955 B2	05-2003	de Queiroz, Ricardo L.	382/239

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Jong Whan Jang, Il Kyun Oh, "Performance Evaluation of Scene Change Detection Algorithms", Communications, 1999. APCC/OECC '99. Fifth Asia-Pacific Conference on ... and Fourth Optoelectronics and Communications Conference, ISBN: 7-5635-0402-8.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/737,064	Applicant(s)/Patent Under Reexamination HORNBACK ET AL.	
	Examiner Sath V. Perungavoor	Art Unit 2624	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,606,413 B1	08-2003	Zeineh, Jack A.	382/232
*	B	US-6,606,636 B1	08-2003	Okazaki et al.	707/104.1
*	C	US-2003/0231246 A1	12-2003	Gindele et al.	348/222.1
*	D	US-6,714,312 B1	03-2004	Hidaka, Atomu	358/1.15
*	E	US-6,909,436 B1	06-2005	Pianykh et al.	345/619
*	F	US-6,983,068 B2	01-2006	Prabhakar et al.	382/162
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.